## IN THE CLAIMS:

Claims 55 and 60 have been amended herein. Please note that all claims currently pending and under consideration in the referenced application are shown below. Please enter these claims as amended. This listing of claims will replace all prior versions and listings of claims in the application.

## **Listing of Claims:**

- 1-36. (Cancelled).
- 37. (Previously Presented) A method of preventing a circuit having a test mode entry function from entering a subsequent test mode after the circuit enters a first test mode, comprising:

initiating a test mode blocking signal after the circuit completes the first test mode; and exclusively controlling the test mode entry function of the circuit with the test mode blocking signal.

- 38. (Previously Presented) The method of claim 37, further comprising generating the test mode blocking signal responsive to a final test latch of the circuit during the first test mode.
- (Previously Presented) The method of claim 38, further comprising originating the test mode blocking signal from the circuit.
  - 40-54. (Cancelled).
- (Currently Amended) The method of claim 37, further comprising resetting the blocking signal in response to a reception o-fof a reset prompt signal.
- (Previously Presented) The method of claim 37, wherein the initiating a test mode blocking signal is in response to receipt of a test-mode-end signal.

- (Previously Presented) The method of claim 37, wherein exclusively controlling
  with the test blocking signal includes gating the test mode entry function with one of an OR,
  NOR, AND, or NAND logic gate.
- 58. (Previously Presented) The method of claim 37, further comprising preserving a state of an output of the circuit responsive to the test mode entry function in response to activation of the test mode blocking signal.
- (Previously Presented) The method of claim 37, wherein the test mode blocking signal is an output of the circuit responsive to the test mode entry function.
- (Currently Amended) The method of claim 37, wherein initiating a test mode blocking signal comprises:

initiating a latch mode;

accepting an input signal;

performing a logic operation on the input signal;

deriving an output signal from a logic operation performed on an input signal while in the latch mode; and

initiating the test mode blocking signal to disable the latch mode.

- 61. (Previously Presented) The method of claim 60, wherein the deriving an output signal comprises deriving a plurality of output signals, and wherein the test mode blocking signal is one of the plurality of output signals.
- (Previously Presented) The method of claim 61, further comprising reestablishing the latch mode through a reset signal.
- 63. (Previously Presented) The method of claim 62, further comprising reestablishing the latch mode exclusively through the reset signal.

64. (Previously Presented) The method in claim 63, wherein reestablishing the latch mode through the reset signal comprises resetting the one of the plurality of output signals that initiated the input lockout mode.